

Abstract

A bit-error-rate (BER) test is a crucial test for wireless devices to pass,
5 since a device with a high BER does not perform at its best. BER tests are
both costly and difficult to perform due to a delay incurred by the device
under test (DUT) 215 and the testing hardware that is variable in nature.
Because the delay is variable, a hardware BER test that can compensate for
the delay is difficult to build and a software BER test that can easily
10 compensate for the delay is very slow. The present invention provides a
method and apparatus that can compensate for the variable delay. By doing
so, a hardware BER test, which is considerably faster than a software BER
test, is easily implemented.